

74LCX652

PRELIMINARY DATA

74LCX652T

LOW VOLTAGE CMOS OCTAL BUS TRANSCEIVER/REGISTER WITH 5V TOLERANT INPUTS AND OUTPUTS

5V TOLERANT INPUTS AND OUTPUTS

HIGH SPEED:
tag =7.0 pg (MAX.) at Va

 t_{PD} =7.0 ns (MAX.) at V_{CC} = 3V

- POWER-DOWN PROTECTION ON INPUTS AND OUTPUTS
- SYMMETRICAL OUTPUT IMPEDANCE: |lo_H| = lo_L = 24 mA (MIN)
- PCI BUS LEVELS GUARANTEED AT 24mA
- BALANCED PROPAGATION DELAYS:
 tplh ≅ tphl
- OPERATING VOLTAGE RANGE:
 V_{CC} (OPR) = 2.0V to 3.6V (1.5V Data Retention)
- PIN AND FUNCTION COMPATIBLE WITH 74 SERIES 652
- LATCH-UP PERFORMANCE EXCEEDS 500mA
- ESD PERFORMANCE: HBM >2000V; MM > 200V

DESCRIPTION

The LCX652 is a low voltage CMOS OCTAL BUS TRANSCEIVERS AND REGISTERS (3-STATE) fabricated with sub-micron silicon gate and double-layer metal wiring C²MOS technology. It is ideal for low power and high speed 3.3V applications; it can be interfaced to 5V signal environment for both inputs and outputs.

M T (Micro Package) (TSSOP Package) ORDER CODES:

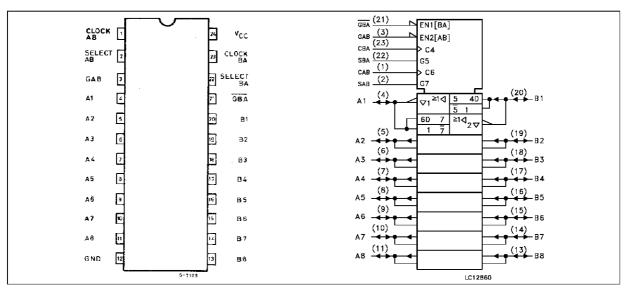
74LCX652M

This device consist of bus transceiver circuits with 3-state output, D type flip-flops, and control circuitry arranged for multiplexed trasmission of data directly from the input bus or from the internal storage registers. Enable (GAB) and (GBA) pins are provided to control the transceiver functions.

Select AB and Select BA control pins are provided to select whether real-time or stored data is transfered. A low input level selects real-time, and a high selects stored data.

Data on the A or B bus, or both, can be stored in the internal D flip-flop by low-to high transitions at the appropriate clock pins (CLOCK AB or CLOCK BA) regardless of the select or enable control

PIN CONNECTION AND IEC LOGIC SYMBOLS



January 1997 1/13

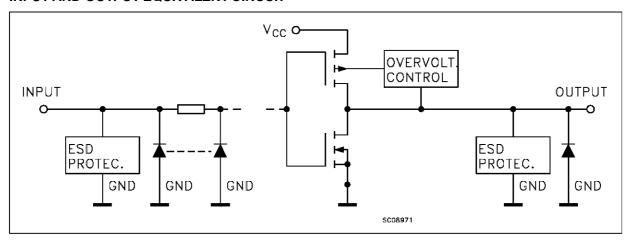
pins. When select AB and select BA are in the real-time transfer mode, it is also possible to store data without using the internal D-type flip-flops by simultaneously enabling GAB or GBA. In this configuration each output reinforces its input.

It has same speed performance at 3.3V than 5V,

AC/ACT family, combined with a lower power consumption.

All inputs and outputs are equipped with protection circuits against static discharge, giving them 2KV ESD immunity and transient excess voltage.

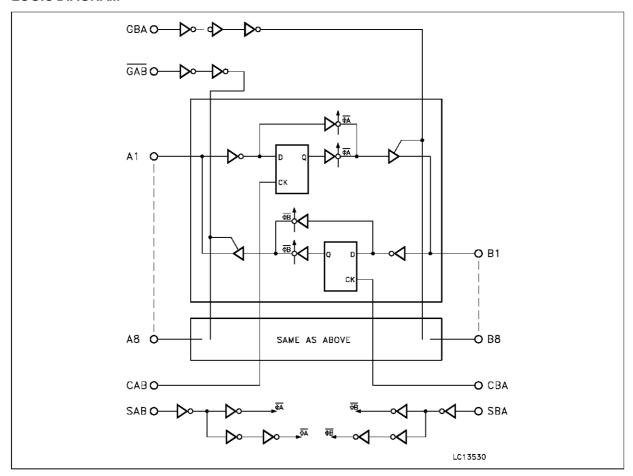
INPUT AND OUTPUT EQUIVALENT CIRCUIT



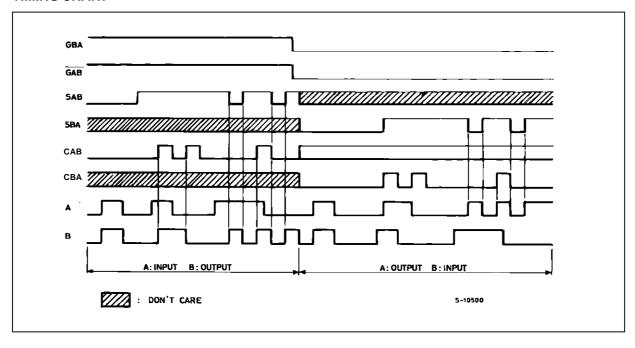
PIN DESCRIPTION

PIN No	SYMBOL	NAME AND FUNCTION		
1	1 CAB A to B Clock Input (LOW to HIGH, Edge-			
2	SAB	Select A to B Source Input		
3	GAB	Direction Control Input		
4, 5, 6, 7, 8, 9, 10, 11	A1 to A8	A Data Inputs/Outputs		
20, 19, 18, 17, 16, 15, 14, 13	B1 to B8	B Data Inputs/Outputs		
21	GBA	Output Enable Input (Active LOW)		
22	SBA	Select B to A Source Input		
23	CBA	B to A Clock Input (LOW to HIGH, Edge-Triggered)		
12	GND	Ground (0V)		
24	V _{CC}	V _{CC} Positive Supply Voltage		

LOGIC DIAGRAM



TIMING CHART



TRUTH TABLE

GAB	GBA	САВ	СВА	SAB	SBA	Α	В	FUNCTION
						INPUTS	INPUTS	Both the A bus and the B bus are inputs
١.		Х	Х	Х	Х	Z	Z	The output functions of the A and B bus are disabled
L	H	Ч	Ч	Х	Х	X INPUTS INPUTS Both the A and B busses are used internal flip-flops. Data on the bus		Both the A and B busses are used as inputs to the internal flip-flops. Data on the bus will be stored on low to high transition of the clock inputs
						OUTPUTS	INPUTS	The A bus are outputs and the B bus are inputs
		Χ*	Х	Х	L	L	L	The data on the B bus are displayed on the A bus
						Н	Н	
		X*		Х	L	L	L	The data on the B bus are displayed on the A bus
L	L					Н	Н	and are stored in the B internal flip-flop on low to high transition of th clock pulse
		X*	Х	Х	Н	Qn	Х	The data stored in the B internal flip-flop are dispayed on the A bus
		X*		Х	Н	L	L	The data on the B bus are stored in the B internal
						Н	Н	flip-flop on low to high transition of the clock pulse. The states of the internal flip-flops propagate directly to the A bus
						INPUTS	OUTPUTS	The A bus are inputs and the B bus are outputs
		Х	X*	L	Х	L	L	The data on the A bus are displayed on the B bus
		^	^		^	Н	Н	
			X*	L	Х	L	L	The data on the A bus are displayed on the B bus
Н	н					Н	Н	and are stored in the A internal flip-flop on low to high transition of the clock pulse
		Х	X*	Н	Х	Х	Qn	The data stored in the A internal flip-flops are displayed on the B bus
			X*	Н	Х	L	L	The data on the A bus are stored in the A internal
						Н	Н	flip-flop on low to high transition of the clock pulse. The states of the internal flip-flops propagate directly on the B bus
						OUTPUTS	OUTPUTS	Both the A bus and the B bus are outputs
Н	L	Х	Х	Н	Н	Qn	Qn	The data stored in the internal flip-flops are displayed on the A and B bus respectively

X : DON'T CARE



Z : HIGH IMPEDANCE

Qn: THE DATA STORED TO THE INTERNAL FLIP-FLOPS BY MOST RECENT LOW TO HIGH TRANSITION OF THE CLOCK INPUTS

^{* :} THE DATA AT THE A AND B BUS WILL BE STORED TO THE INTERNAL FLIP-FLOPS ON EVERY LOW TO HIGH TRANSITION OF THE CLOCK INPUTS

ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Value	Unit
Vcc	Supply Voltage	-0.5 to + 7.0	V
V_{I}	DC Input Voltage	-0.5 to + 7.0	V
Vo	DC Output Voltage (Vcc=0V)	-0.5 to + 7.0	V
Vo	DC Output Voltage (High or Low State) (note1)	-0.5 to V _{CC} + 0.5	V
I _{IK}	DC Input Diode Current	- 50	mA
I _{OK}	DC Output Diode Current (note2)	± 50	mA
lo	DC Output Source/Sink Current	± 50	mA
Icc	DC Supply Current per Supply Pin	± 100	mA
I _{GND}	DC Ground Current per Supply Pin	± 100	mA
T _{stg}	Storage Temperature	-65 to +150	°C
TL	Lead Temperature (10 sec)	300	°C

Absolute Maximum Ratings are those values beyond which damage to the device may occur. Functional operation under these condition is not implied.

RECOMMENDED OPERATING CONDITIONS

Symbol	Parameter	Value	Unit
Vcc	Supply Voltage (note 1)	2.0 to 3.6	V
VI	Input Voltage	0 to 5.5	V
Vo	Output Voltage (V _{CC} =0V)	0 to 5.5	V
Vo	Output Voltage (High or Low State)	0 to V _{CC}	V
I _{OH} , I _{OL}	High or Low Level Output Current (V _{CC} = 3.0 to 3.6V)	± 24	mA
I _{OH} , I _{OL}	High or Low Level Output Current (V _{CC} = 2.7 to 3.0V)	± 12	mA
T _{op}	Operating Temperature:	-40 to +85	°C
dt/dv	Input Transition Rise or Fall Rate (V _{CC} = 3.0V) (note 2)	0 to 10	ns/V

¹⁾ Truth Table guaranteed: 1.5V to 3.6V 2) V_{IN} from 0.8V to 2.0V

¹⁾ lo absolute maximum rating must be observed 2) Vo < GND, Vo > Vcc

DC SPECIFICATIONS

Symbol	Parameter	Test	Condit	Val	ue	Unit	
		Vcc	Vcc -40 to 85		85 °C		
		(V)			Min.	Max.	
V_{IH}	High Level Input Voltage	2.7 to 3.6			2.0		V
V_{IL}	Low Level Input Voltage	2.7 10 3.0				0.8	V
VoH	High Level Output Voltage	2.7 to 3.6	Vı =	I _O =-100 μA	V _{CC} -0.2		
		2.7	V_{IH} or	I _O =-12 mA	2.2		V
		3.0	V ₁₁		2.4]
		3.0		I _O =-24 mA	2.2		
V_{OL}	Low Level Output Voltage	2.7 to 3.6	Vı =	Ι _Ο =100 μΑ		0.2	
		2.7	V _{IH} or	I _O =12 mA		0.4	V
		3.0	V _{IL}	I _O =16 mA		0.4	
		3.0		I _O =24 mA		0.55	
l _l	Input Leakage Current	2.7 to 3.6	V _I =	0 to 5.5 V		±5	μΑ
loz	3 State Output Leakage Current	2.7 to 3.6		$V_I = V_{IH} \text{ or } V_{IL}$ $V_O = 0 \text{ to } 5.5 \text{V}$		±5	μА
I _{off}	Power Off Leakage Current	0	V_I or $V_O = 5.5V$			100	μΑ
Icc	Quiescent Supply Current	2.7 to 3.6	V _I = V	V _I = V _{CC} or GND		10	
			V _I or V _O = 3.6 to 5.5V			±10	μΑ
Δlcc	ICC incr. per input	2.7 to 3.6	V _{IH} =	V _{CC} -0.6V		500	μΑ

DYNAMIC SWITCHING CHARACTERISTICS

Symbol	Parameter	Tes	st Conditions	Value			Unit
		Vcc		T _A = 25 °C			
		(V)		Min.	Тур.	Max.	
V _{OLP}	Dynamic Low Voltage Quiet Output	3.3	C _L = 50 pF		0.8		
Volv	(note 1)		$V_{IL} = 0 V$ $V_{IH} = 3.3V$		-0.8		V

¹⁾ Number of outputs defined as "n". Measured with "n-1" outputs switching from HIGH to LOW or LOW to HIGH. The remaining output is measured in the LOW state.



AC ELECTRICAL CHARACTERISTICS ($C_L = 50 \text{ pF}, R_L = 500 \Omega$, Input $t_r = t_f = 2.5 \text{ ns}$)

Symbol	Parameter	Test (Condition	Va	Unit		
		Vcc	Waveform	-40 to	85 °C		
		(V)		Min.	Max.		
t _{PLH}	Propagation_Delay Time	2.7	1	1.5	9.5	ns	
t _{PHL}	CK to Q or Q	3.0 to 3.6	'	1.5	8.5	115	
t _{PLH}	Propagation Delay Time	2.7	1	1.5	8.0	ns	
t _{PHL}	An or Bn to Q or Q	3.0 to 3.6	I	1.5	7.0		
t _{PLH}	Propagation Delay Time	2.7	1	1.5	9.5		
t _{PHL}	SELECT to Q or Q	3.0 to 3.6	'	1.5	8.5	ns	
t _{PZL}	Output Enable Time	2.7	2	1.5	9.5	ns	
t _{PZH}		3.0 to 3.6	2	1.5	8.5		
t _{PLZ}	Output Disable Time	2.7	2	1.5	9.5	ns	
t _{PHZ}		3.0 to 3.6		1.5	8.5		
ts	Setup Time, HIGh or LOW Level Data	2.7	1	2.5		ns	
	to Ck	3.0 to 3.6	'	2.5		115	
t _h	Hold Time, HIGh or LOW Level Data to	2.7	1	1.5		ns	
	Ck	3.0 to 3.6	'	1.5		115	
t _w	CK Pulse Width, HIGH or LOW	2.7	3	4.0		ne	
		3.0 to 3.6	3	3.3		ns	
f _{MAX}	Clock Pulse Frequency	3.0 to 3.6	1	150		MHz	
tostz tosht	Output to Output Skew Time (note 1, 2)	3.0 to 3.6			1.0	ns	

¹⁾ Skew is defined as the absolute value of the difference between the actual propagation delay for any two outputs of the same device switching in the same direction, either HIGH or LOW (tosuh = |tpl.hm - tpl.hm|, toshL = |tpl.hm - tpl.hm|)

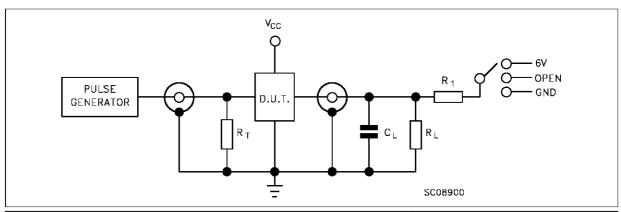
CAPACITIVE CHARACTERISTICS

Symbol	Parameter	Tes	Test Conditions		Value		Unit
		Vcc		T _A = 25 °C			
		(V)		Min.	Тур.	Max.	
C _{IN}	Input Capacitance	3.3	$V_{IN} = 0$ to V_{CC}		6		pF
C _{i/o}	I/O Capacitance	3.3	$V_{IN} = 0$ to V_{CC}		10		pF
C _{PD}	Power Dissipation Capacitance (note 1)	3.3	$f_{IN} = 10MHz$ $V_{IN} = 0 \text{ or } V_{CC}$		TBD		pF

¹⁾ C_{PD} is defined as the value of the IC's internal equivalent capacitance which is calculated from the operating current consumption without load. Average operting current can be obtained by the following equation. $I_{CC}(opr) = C_{PD} \bullet V_{CC} \bullet f_{IN} + I_{CC}/n$ (per circuit)

²⁾ Parameter guaranteed by design

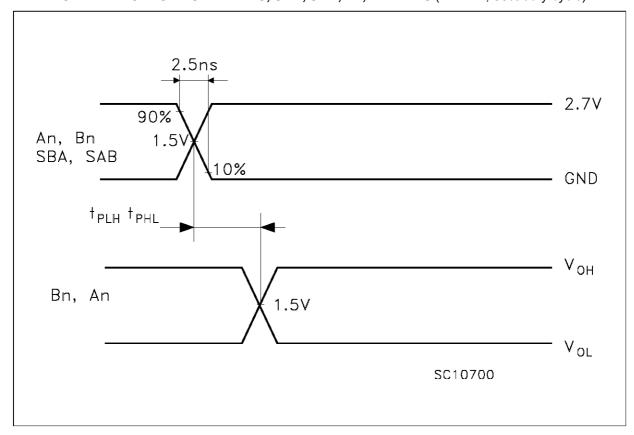
TEST CIRCUIT



TEST	SWITCH
tplh, tphl	Open
t _{PZL} , t _{PLZ}	6V
t _{PZH} , t _{PHZ}	GND

 $C_L = 50 \text{ pF}$ or equivalent (includes jig and probe capacitance)

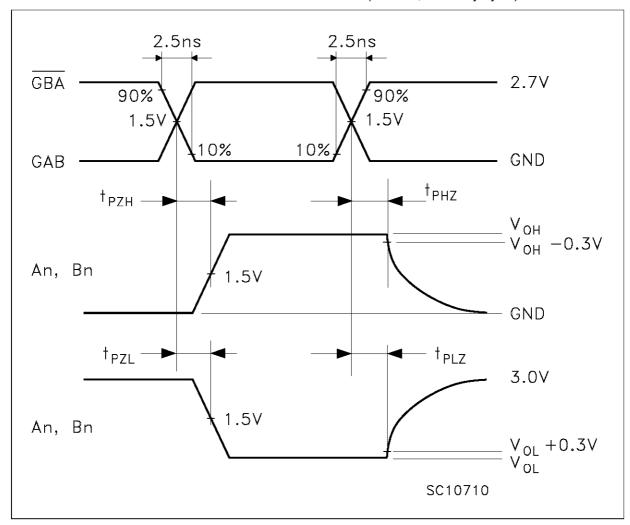
WAVEFORM 1: PROPAGATION DELAYS, SAB, SBA, An, Bn TIMES (f=1MHz; 50% duty cycle)



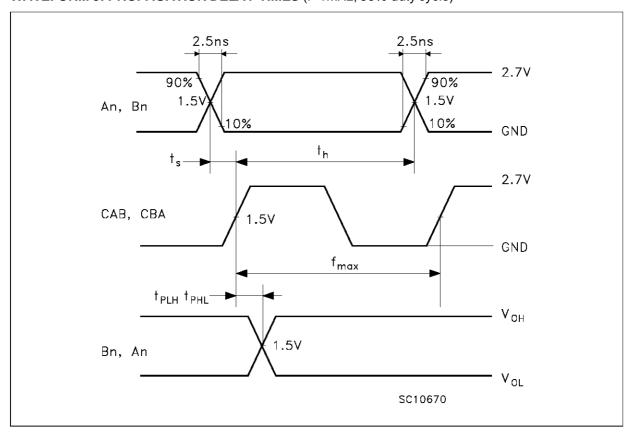
 $R_L = R_1 = 500\Omega$ or equivalent

 $R_T = Z_{OUT}$ of pulse generator (typically 50Ω)

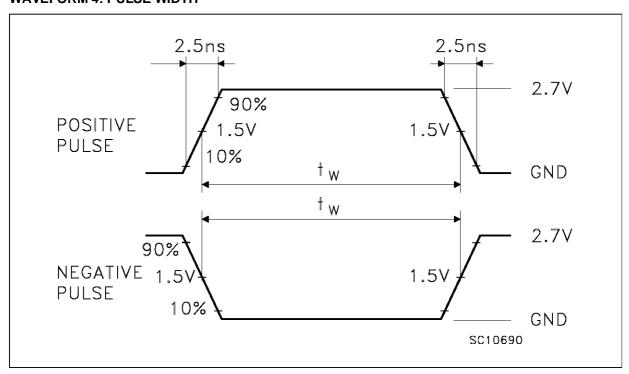
WAVEFORM 2: OUTPUT ENABLE AND DISABLE TIMES (f=1MHz; 50% duty cycle)



WAVEFORM 3: PROPAGATION DELAY TIMES (f=1MHz; 50% duty cycle)

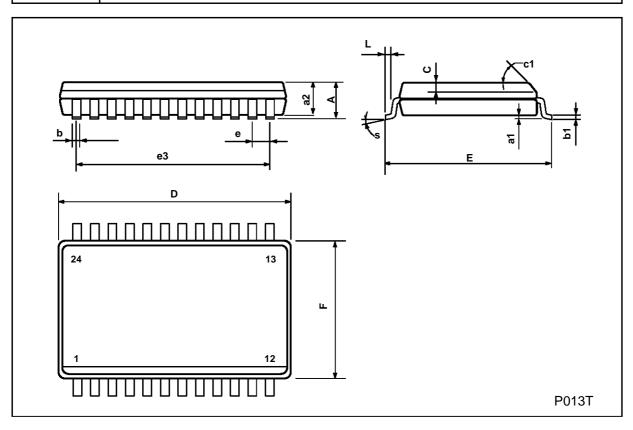


WAVEFORM 4: PULSE WIDTH



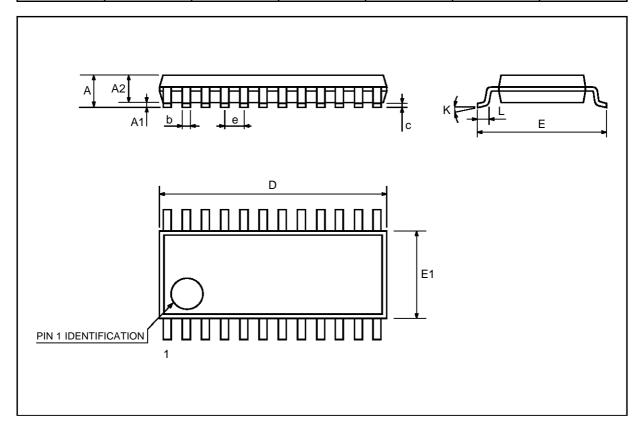
SO24 MECHANICAL DATA

DIM.		mm		inch					
DIIVI.	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.			
А			2.65			0.104			
a1	0.10		0.20	0.004		0.007			
a2			2.45			0.096			
b	0.35		0.49	0.013		0.019			
b1	0.23		0.32	0.009		0.012			
С		0.50			0.020				
c1			45 ((typ.)					
D	15.20		15.60	0.598		0.614			
Е	10.00		10.65	0.393		0.420			
е		1.27			0.05				
e3		13.97			0.55				
F	7.40		7.60	0.291		0.299			
L	0.50		1.27	0.19		0.050			
S		8 (max.)							



TSSOP24 MECHANICAL DATA

DIM.		mm		inch			
2	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.	
А			1.1			0.433	
A1	0.05	0.10	0.15	0.002	0.004	0.006	
A2	0.85	0.9	0.95	0.335	0.354	0.374	
b	0.19		0.30	0.0075		0.0118	
С	0.09		0.2	0.0035		0.0079	
D	7.7	7.8	7.9	0.303	0.307	0.311	
E	6.25	6.4	6.5	0.246	0.252	0.256	
E1	4.3	4.4	4.48	0.169	0.173	0.176	
е		0.65 BSC			0.0256 BSC		
К	0°	4°	8°	0°	4°	8°	
L	0.50	0.60	0.70	0.020	0.024	0.028	



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